

Notice of References Cited	Application/Control No. 10/502,465		Applicant(s)/Patent Under Reexamination NASSIOPOULOU ET AL.	
	Examiner Frederick F. Rosenberger		Art Unit 2884	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,832,523	12-2004	Benzel et al.	73/763
*	B	US-6,759,265	07-2004	Artmann et al.	438/53
	C	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	Halimaoui, A. "Porous Silicon Formation by Anodisation." in: Canham, L., Properties of Porous Silicon (England, Short Run Press, 1997), pp. 12-14.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.